

Problem 1 (25 points)

Consider a homogeneous p-type Si semiconductor ($N_A = 1 \times 10^{17} \text{ cm}^{-3}$) in thermal equilibrium at $t < 1 \mu\text{s}$. An external source is turned on at $t = 1 \mu\text{s}$ for a period of $0.1 \mu\text{s}$ and produces excess carriers uniformly at the rate of $g = 10^{21} \text{ cm}^{-3} \text{ s}^{-1}$.

Assume:

$$D_n = 20 \frac{\text{cm}^2}{\text{s}}, D_p = 10 \frac{\text{cm}^2}{\text{s}}, \tau_n = 10^{-6} \text{ s}, \tau_p = 10^{-7} \text{ s}$$

- a) (5 points) Determine the expression of $\delta n_p(t)$ for $0 \leq t \leq 1.0 \mu\text{s}$
- b) (5 points) Determine the expression of $\delta n_p(t)$ for $1.0 \leq t \leq 1.1 \mu\text{s}$
- c) (10 points) Determine the expression of $\delta n_p(t)$ for $1.1 \mu\text{s} \leq t \leq \infty$
- d) (5 points) Plot $\delta n_p(t)$ for $t = 0$ to $t = \infty$

Problem 2 (25 points)

Consider a silicon pn junction with the following parameters at $T = 300\text{K}$:

$$N_A = 5 \times 10^{15} \text{ cm}^{-3}, \tau_p = 10^{-7} \text{ s}, \tau_n = 10^{-6} \text{ s}, \frac{kT}{e} = 0.026 \text{ V}$$
$$\mu_p = 400 \text{ cm}^2 / \text{V.s}, \mu_n = 1000 \text{ cm}^2 / \text{V.s}, n_i = 1.5 \times 10^{10} \text{ cm}^{-3}$$

- a) (10 points) Determine N_D such that the ratio of the electron current to total current in the depletion region is 0.75
- b) (10 points) The total current when $V_a = 0.6$ is 0.1mA, determine the cross-sectional area
- c) (5 points) Sketch the energy-band diagram across the pn junction corresponding to part (b).

Problem 3 (25 points)

Consider a Si pn junction with $N_A = 1 \times 10^{17} \text{ cm}^{-3}$ and $N_D = 1 \times 10^{15} \text{ cm}^{-3}$.

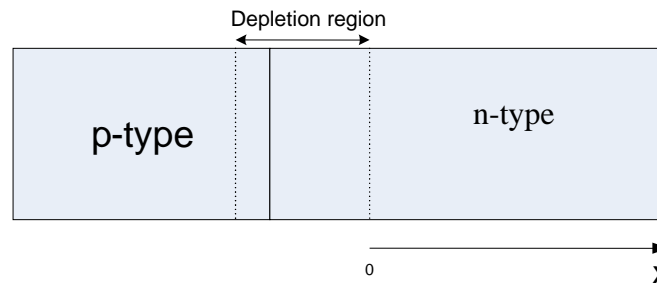
The critical electric field is $3 \times 10^5 \text{ V/cm}$ and $\epsilon_s = 11.7 \times 8.85 \times 10^{-14} \text{ F/cm}$.

- a) (5 points) Is this a symmetrical or one-sided pn junction?
- b) (10 points) Determine the breakdown voltage. Plot the electric field along the pn junction at this voltage.
- c) (5 points) The measured capacitance at the breakdown voltage is 1pF. Determine the cross-sectional area.

Problem 4 (25 points)

Consider a silicon pn junction at $T = 300\text{ K}$, $N_A = 5 \times 10^{16}\text{ cm}^{-3}$, $N_D = 1 \times 10^{16}\text{ cm}^{-3}$. The minority carrier lifetimes are $\tau_n = 0.01\text{ }\mu\text{s}$ and $\tau_p = 0.01\text{ }\mu\text{s}$. The junction is forward biased with $V_A = 0.6\text{ V}$. The minority carrier diffusion coefficients are $D_n = 25\text{ cm}^2/\text{s}$, $D_p = 10\text{ cm}^2/\text{s}$.

$$n_i = 1.5 \times 10^{10}\text{ cm}^{-3}, \frac{kT}{e} = 0.026\text{ V}$$



- (5 points) Calculate the excess hole concentration as a function of x in the n side (see the figure above).
- (10 points) Calculate the hole diffusion current density at $x = 2L_p$
- (10 points) Calculate the electron current at $x = 2L_p$